# High Speed, High Gain Bipolar NPN Power Transistor

## with Integrated Collector–Emitter Diode and Built–in Efficient Antisaturation Network

The BUL45D2G is state–of–art High Speed High gain BiPolar transistor (H2BIP). High dynamic characteristics and lot–to–lot minimum spread ( $\pm 150$  ns on storage time) make it ideally suitable for light ballast applications. Therefore, there is no need to guarantee an h<sub>FE</sub> window. It's characteristics make it also suitable for PFC application.

#### Features

- Low Base Drive Requirement
- High Peak DC Current Gain

- Extremely Low Storage Time Min/Max Guarantees Due to the H2BIP Structure which Minimizes the Spread
- Integrated Collector-Emitter Free Wheeling Diode
- Fully Characterized and Guaranteed Dynamic V<sub>CE(sat)</sub>
- "6 Sigma" Process Providing Tight and Reproductible Parameter Spreads
- These Devices are Pb-Free and are RoHS Compliant\*

MAXIMUM RATINGS								
Rating	Symbol	Value	Unit					
Collector-Emitter Sustaining Voltage	V <sub>CEO</sub>	400	Vdc					
Collector-Base Breakdown Voltage	V <sub>CBO</sub>	700	Vdc					
Collector-Emitter Breakdown Voltage	V <sub>CES</sub>	700	Vdc					
Emitter-Base Voltage	V <sub>EBO</sub>	12	Vdc					
Collector Current – Continuous	Ι <sub>C</sub>	5	Adc					
Collector Current – Peak (Note 1)	I <sub>CM</sub>	10	Adc					
Base Current – Continuous	I <sub>B</sub>	2	Adc					
Base Current – Peak (Note 1)	I <sub>BM</sub>	4	Adc					
Total Device Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	P <sub>D</sub>	75 0.6	W W/°C					
Operating and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	-65 to +150	°C					

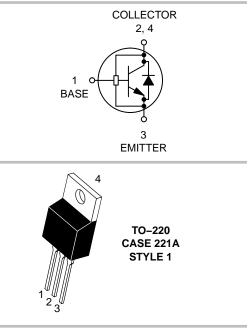
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Pulse Test: Pulse Width = 5 ms, Duty Cycle  $\leq$  10%.



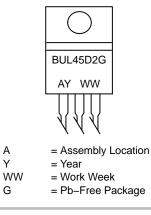
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## POWER TRANSISTOR 5.0 AMPERES, 700 VOLTS, 75 WATTS



### MARKING DIAGRAM



#### **ORDERING INFORMATION**

Device	Package	Shipping
BUL45D2G	TO–220 (Pb–Free)	50 Units / Rail

\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### THERMAL CHARACTERISTICS

Characteristics	Symbol	Мах	Unit
Thermal Resistance, Junction-to-Case	$R_{ ext{ heta}JC}$	1.65	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{\thetaJA}$	62.5	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 5 Seconds	ΤL	260	°C

## **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = $25^{\circ}$ C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					
Collector–Emitter Sustaining Voltage $(I_C = 100 \text{ mA}, L = 25 \text{ mH})$	V <sub>CEO(sus)</sub>	400	450	_	Vdc
Collector–Base Breakdown Voltage (I <sub>CBO</sub> = 1 mA)	V <sub>CBO</sub>	700	910	_	Vdc
Emitter–Base Breakdown Voltage (I <sub>EBO</sub> = 1 mA)	V <sub>EBO</sub>	12	14.1	-	Vdc
Collector Cutoff Current ( $V_{CE}$ = Rated $V_{CEO}$ , $I_B$ = 0)	I <sub>CEO</sub>	_	-	100	μAdc
Collector Cutoff Current $(V_{CE} = Rated V_{CES}, V_{EB} = 0)$ @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C $(V_{CE} = 500 V, V_{EB} = 0)$ @ T <sub>C</sub> = 125°C	ICES	- -		100 500 100	μAdc
Emitter–Cutoff Current ( $V_{EB} = 10 \text{ Vdc}, I_C = 0$ )	I <sub>EBO</sub>	_	_	100	μAdc
ON CHARACTERISTICS	II				
Base-Emitter Saturation Voltage ( $I_C = 0.8 \text{ Adc}, I_B = 80 \text{ mAdc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$	V <sub>BE(sat)</sub>	-	0.8 0.7	1 0.9	Vdc
$(I_C = 2 \text{ Adc}, I_B = 0.4 \text{ Adc})$ @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$		- -	0.89 0.79	1 0.9	
Collector-Emitter Saturation Voltage ( $I_C = 0.8 \text{ Adc}, I_B = 80 \text{ mAdc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$ ( $I_C = 2 \text{ Adc}, I_B = 0.4 \text{ Adc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$ ( $I_C = 0.8 \text{ Adc}, I_B = 40 \text{ mAdc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$	V <sub>CE(sat)</sub>	- - - -	0.28 0.32 0.32 0.38 0.46 0.62	0.4 0.5 0.5 0.6 0.75 1	Vdc
DC Current Gain ( $I_C = 0.8 \text{ Adc}, V_{CE} = 1 \text{ Vdc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$ ( $I_C = 2 \text{ Adc}, V_{CE} = 1 \text{ Vdc}$ ) @ $T_C = 25^{\circ}\text{C}$ @ $T_C = 125^{\circ}\text{C}$	h <sub>FE</sub>	22 20 10 7	34 29 14 9.5	- - -	_
DIODE CHARACTERISTICS			*		
Forward Diode Voltage $(I_{EC} = 1 \text{ Adc})$ @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C $(I_{EC} = 2 \text{ Adc})$ @ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	V <sub>EC</sub>		1.04 0.7 1.2	1.5 - 1.6	V
$(I_{EC} = 0.4 \text{ Adc})$ $@ T_C = 25^{\circ}C$ $@ T_C = 125^{\circ}C$		-	0.85 0.62	1.2 -	

	Symbol	Min	Тур	Max	Unit			
DIODE CHARACTERISTIC	cs							
Forward Recovery Time (s $(I_F = 1 \text{ Adc}, \text{ di/dt} = 10 \text{ A})$				T <sub>fr</sub>				ns
@ T <sub>C</sub> = 25°C (I <sub>F</sub> = 2 Adc, di/dt = 10 A @ T <sub>C</sub> = 25°C		-	330 360	_				
$(I_F = 0.4 \text{ Adc}, \text{ di/dt} = 10)$ @ $T_C = 25^{\circ}\text{C}$	A/μs)				_	320	_	
OYNAMIC CHARACTERIS	STICS			<u> </u>		Į	<u></u>	
Current Gain Bandwidth ( $I_C = 0.5 \text{ Adc}, V_{CE} = 10$	) Vdc, f = 1 MHz)			f <sub>T</sub>	_	13	_	MHz
Output Capacitance ( $V_{CB} = 10 \text{ Vdc}, I_E = 0, 1$	f = 1 MHz)			C <sub>ob</sub>	_	50	75	pF
Input Capacitance (V <sub>EB</sub> = 8 Vdc)				C <sub>ib</sub>	_	340	500	pF
OYNAMIC SATURATION	VOLTAGE							
Dynamic Saturation Voltage:	I <sub>C</sub> = 1 A I <sub>B1</sub> = 100 mA	@ 1 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	V <sub>CE(dsat)</sub>	-	3.7 9.4		V
Determined 1 μs and 3 μs respectively after rising I <sub>B1</sub> reaches	V <sub>CC</sub> = 300 V	@ 3 µs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C		-	0.35 2.7		V
90% of final I <sub>B1</sub>	I <sub>C</sub> = 2 A I <sub>B1</sub> = 0.8 A	@ 1 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C		-	3.9 12		V
	$V_{CC} = 300 V$	@ 3 µs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C		-	0.4 1.5		V
SWITCHING CHARACTER	RISTICS: Resistive	Load (D (	-	dth – 20 us)				
Turn-on Time	$I_C = 2 \text{ Adc}, I_{B1} = 0$ $I_{B2} = 1 \text{ Adc}$	0.4 Adc	@ $T_C = 25^{\circ}C$ @ $T_C = 125^{\circ}C$	t <sub>on</sub>	-	90 105	150 -	ns
Turn–off Time	V <sub>CC</sub> = 300 V	dc	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>off</sub>	-	1.15 1.5	1.3	μs
Turn-on Time	I <sub>C</sub> = 2 Adc, I <sub>B1</sub> = 0 I <sub>B2</sub> = 0.4 Ad		@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>on</sub>	-	90 110	150 -	ns
Turn-off Time	$V_{CC} = 300 V$	dc	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>off</sub>	2.1	- 3.1	2.4	μs
SWITCHING CHARACTER	RISTICS: Inductive	Load (Val		= 15 V. L = 20	)0 µH)			
Fall Time	I <sub>C</sub> = 1 Adc I <sub>B1</sub> = 100 mA		@ $T_C = 25^{\circ}C$ @ $T_C = 125^{\circ}C$	t <sub>f</sub>		90 93	150 -	ns
Storage Time	$I_{B2} = 500 \text{ mAdc}$		@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>s</sub>	-	0.72 1.05	0.9	μs
Crossover Time			@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>c</sub>		95 95	150 -	ns
Fall Time	I <sub>C</sub> = 2 Adc I <sub>B1</sub> = 0.4 Ad		@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	t <sub>f</sub>		80 105	150 _	ns
Storage Time	$I_{B2} = 0.4 \text{ Adc}$		@ $T_C = 25^{\circ}C$ @ $T_C = 125^{\circ}C$	t <sub>s</sub>	1.95	- 2.9	2.25	μS
Crossover Time			@ $T_C = 25^{\circ}C$ @ $T_C = 125^{\circ}C$	t <sub>c</sub>	_	225 450	300	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

### **TYPICAL STATIC CHARACTERISTICS**

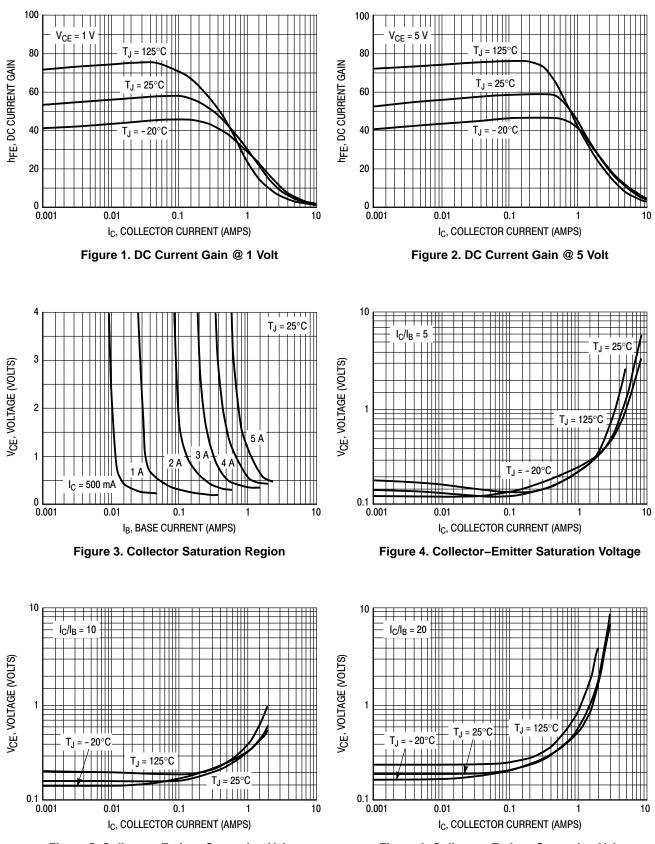
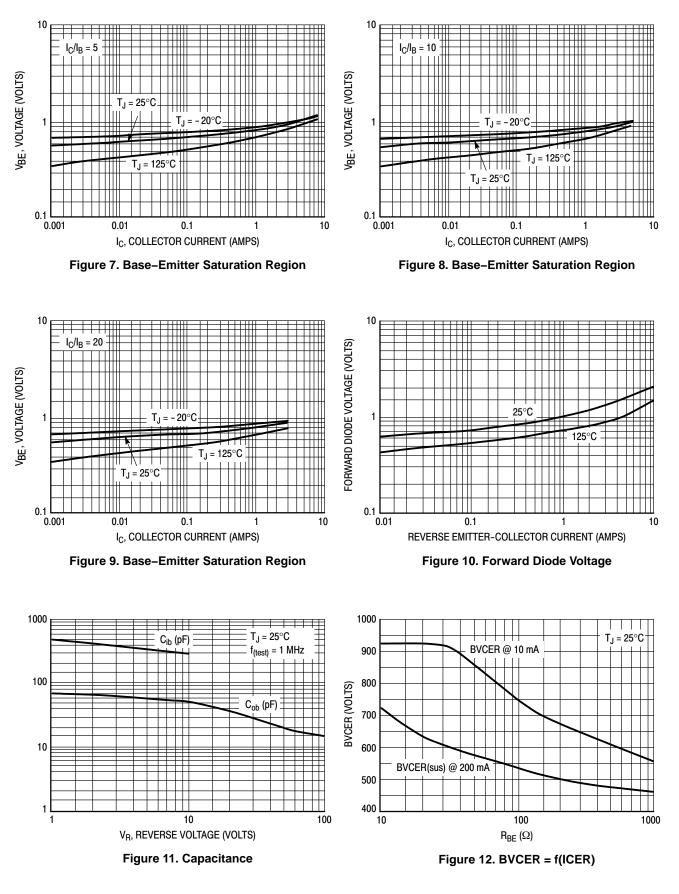


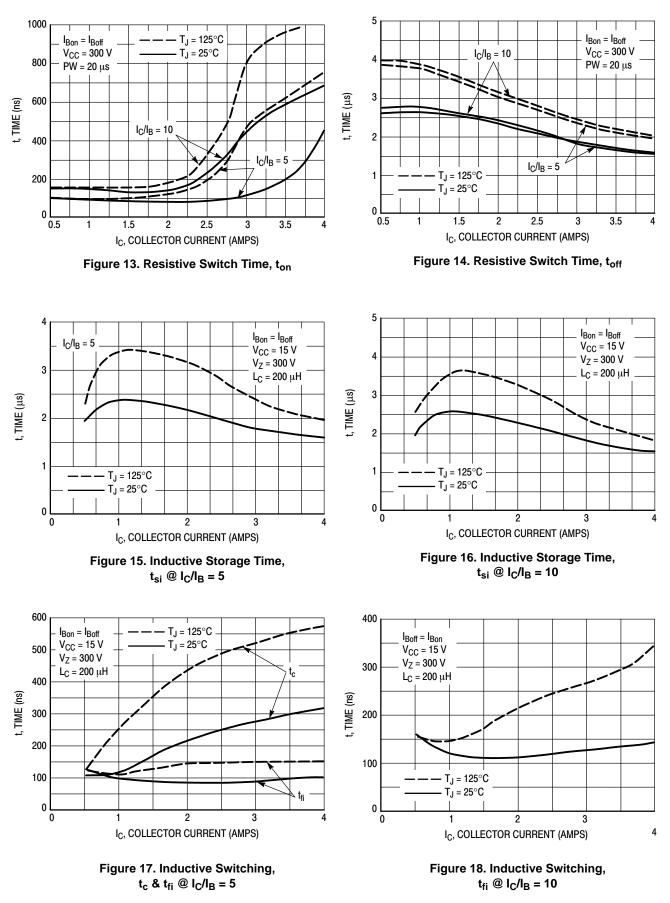
Figure 5. Collector–Emitter Saturation Voltage



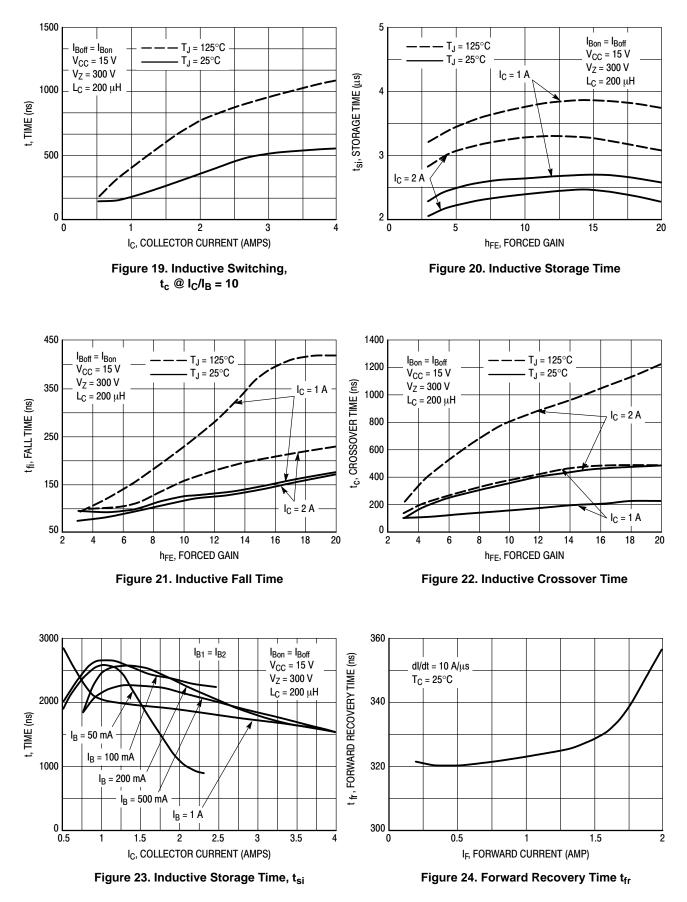




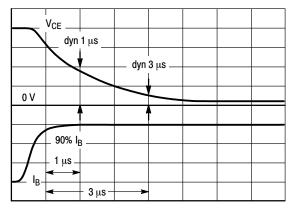
#### **TYPICAL SWITCHING CHARACTERISTICS**



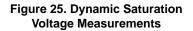
#### **TYPICAL SWITCHING CHARACTERISTICS**

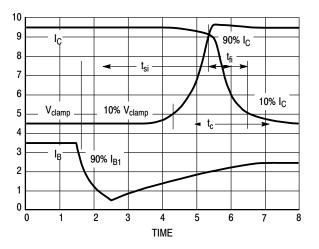


## **TYPICAL SWITCHING CHARACTERISTICS**











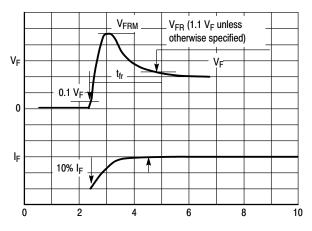
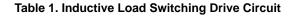
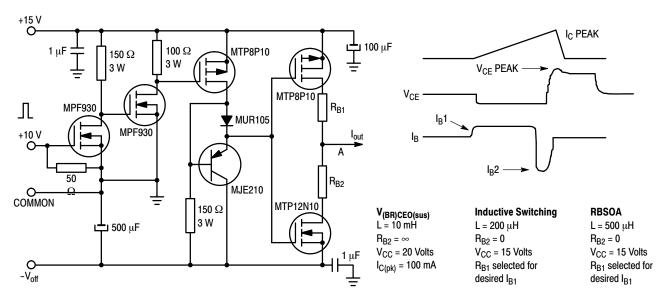


Figure 27. t<sub>fr</sub> Measurements

### **TYPICAL SWITCHING CHARACTERISTICS**





#### **TYPICAL CHARACTERISTICS**

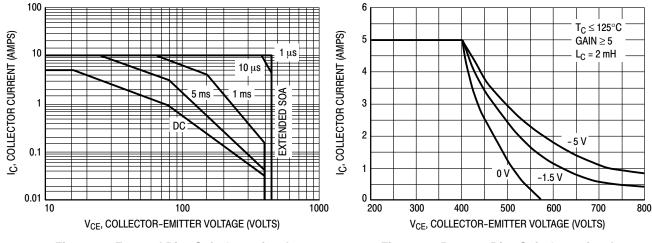


Figure 28. Forward Bias Safe Operating Area

Figure 29. Reverse Bias Safe Operating Area

#### **TYPICAL CHARACTERISTICS**

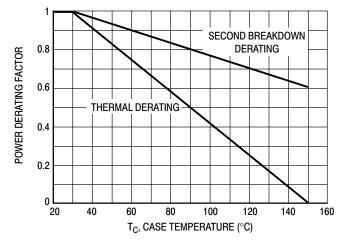
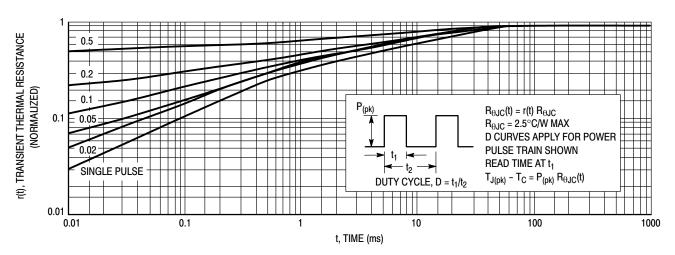


Figure 30. Forward Bias Power Derating

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate  $I_C-V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate. The data of Figure 28 is based on  $T_C = 25^{\circ}C$ ;  $T_{J(pk)}$  is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when  $T_C > 25^{\circ}C$ . Second breakdown limitations do not derate the same as thermal limitations. Allowable current at the voltages shown on Figure 28 may be found at any case temperature by using the appropriate curve on Figure 30.

 $T_{J(pk)}$  may be calculated from the data in Figure 31. At any case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown. For inductive loads, high voltage and current must be sustained simultaneously during turn–off with the base to emitter junction reverse biased. The safe level is specified as a reverse biased safe operating area (Figure 29). This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode.



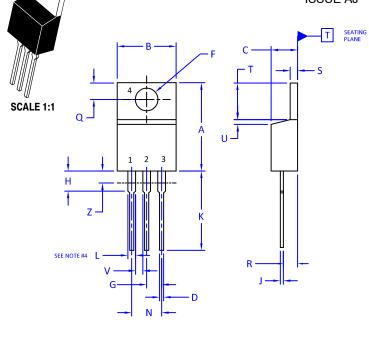
#### **TYPICAL THERMAL RESPONSE**

Figure 31. Typical Thermal Response ( $Z_{\theta JC}(t)$ ) for BUL45D2

DATE 05 NOV 2019



**TO-220** CASE 221A-09 ISSUE AJ



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 2009.

2. CONTROLLING DIMENSION: INCHES

3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE ALLOWED.

4. MAX WIDTH FOR F102 DEVICE = 1.35MM

	INCHES		MILLIME	ETERS	
DIM	MIN.	MAX.	MIN.	MAX.	
А	0.570	0.620	14.48	15.75	
В	0.380	0.415	9.66	10.53	
С	0.160	0.190	4.07	4.83	
D	0.025	0.038	0.64	0.96	
F	0.142	0.161	3.60	4.09	
G	0.095	0.105	2.42	2.66	
Н	0.110	0.161	2.80	4.10	
J	0.014	0.024	0.36	0.61	
К	0.500	0.562	12.70	14.27	
L	0.045	0.060	1.15	1.52	
Ν	0.190	0.210	4.83	5.33	
Q	0.100	0.120	2.54	3.04	
R	0.080	0.110	2.04	2.79	
S	0.045	0.055	1.15	1.41	
Т	0.235	0.255	5.97	6.47	
U	0.000	0.050	0.00	1.27	
V	0.045		1.15		
Z		0.080		2.04	

STYLE 1: PIN 1. 2. 3. 4.	BASE COLLECTOR EMITTER COLLECTOR	STYLE 2: PIN 1. 2. 3. 4.	BASE EMITTER COLLECTOR EMITTER	STYLE 3: PIN 1. 2. 3. 4.	CATHODE ANODE GATE ANODE	STYLE 4: PIN 1. 2. 3. 4.	MAIN TERMINAL 1 MAIN TERMINAL 2 GATE MAIN TERMINAL 2
STYLE 5: PIN 1. 2. 3. 4.	DRAIN SOURCE		CATHODE ANODE	3.	CATHODE ANODE CATHODE ANODE	STYLE 8: PIN 1. 2. 3. 4.	ANODE EXTERNAL TRIP/DELAY
STYLE 9: PIN 1. 2. 3. 4.	COLLECTOR EMITTER	STYLE 10: PIN 1. 2. 3. 4.	GATE SOURCE DRAIN	STYLE 11: PIN 1. 2. 3. 4.		STYLE 12 PIN 1. 2. 3. 4.	MAIN TERMINAL 1 MAIN TERMINAL 2 GATE NOT CONNECTED

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